

What is claimed is:

1. A method of fabricating an integrated circuit comprising:  
forming a diffusion barrier layer pattern on a semiconductor substrate;  
forming a SOG layer containing impurities on the entire surface of the  
semiconductor substrate;  
5 additionally implanting impurity ions into the SOG layer by a plasma ion  
implantation method to increase the concentration of impurities in the SOG  
layer; and  
diffusing the impurity ions contained in the SOG layer having the  
10 increased concentration of impurities into the semiconductor substrate by a  
solid phase diffusion method to form shallow junctions.

2. The method of claim 1, wherein the SOG layer is formed by spin-  
coating and densifying a liquid silicate glass including one of P, B, In, As, and  
15 Sb doping elements.

3. The method of claim 1, wherein the SOG layer is formed by  
chemical vapor deposition (CVD) using a compound gas including  $\text{SiH}_4$ ,  $\text{O}_2$ ,  
and one of P, B, In, As, and Sb doping elements.

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4. The method of claim 1, wherein the concentration of impurities of  
the SOG layer is increased using a plasma ion implanter including a Plasma  
Immersion Ion Implanter (PIII) and an Ion Shower Implanter (ISI).

✓ 5. The method of claim 1, wherein the maximum impurity implantation concentration of the SOG layer additionally implanted with the impurity ions is adjusted to  $10^{19} - 10^{23} \text{ cm}^{-3}$ .

5 6. The method of claim 1, wherein impurity ions are implanted into only portions of the SOG layer formed on the diffusion barrier layer and the semiconductor substrate when the impurity ions are additionally implanted into the SOG layer.

10 7. The method of claim 1, wherein the shallow junctions are formed by the solid phase diffusion method using one of rapid thermal annealing (RTA), spike annealing, and laser annealing.

15 8. The method of claim 7, wherein in the RTA, the semiconductor substrate on which the SOG layer having the increased concentration of impurities is formed is rapidly thermally annealed at a temperature of 950 – 1150 °C for 1 – 1000 seconds in an inert gas atmosphere.

20 9. The method of claim 7, wherein in the spike annealing, the semiconductor substrate on which the SOG layer having the increased concentration of impurities is formed is rapidly thermally annealed at a temperature of 950 – 1200 °C in an inert gas atmosphere.

10. The method of claim 1, wherein the shallow junctions have a doping depth of 50nm or less on the semiconductor substrate and a doping concentration of  $10^{18} - 10^{22} \text{cm}^{-3}$ .

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11. A method of fabricating an integrated circuit comprising:

forming a gate pattern on a semiconductor substrate;

forming a SOG layer containing impurities on the entire surface of the semiconductor substrate;

10 additionally implanting impurity ions into portions of the SOG layer formed on the gate pattern and the semiconductor substrate by a plasma ion implantation method to selectively increase the concentration of impurities of the SOG layer; and

15 diffusing the impurity ions contained in the SOG layer into the semiconductor substrate by a solid phase diffusion method to form shallow junctions having a LDD region and a highly doped source/drain region self-aligned underneath both sidewalls of the gate pattern.

12. The method of claim 11, wherein the ratio of the thickness of the SOG layer to the height of a gate electrode constituting the gate pattern is  
20 between 1:1.5 and 1:10.

13. The method of claim 11, wherein the SOG layer is formed by spin-coating and densifying a liquid silicate glass including one of P, B, In, As, and Sb doping elements.

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14. The method of claim 11, wherein the SOG layer is formed by CVD using a compound gas including SiH<sub>4</sub>, O<sub>2</sub>, and one of P, B, In, As, and Sb doping elements.

5 15. The method of claim 11, wherein the concentration of impurities of the SOG layer is selectively increased using a plasma ion implanter including a PIII or an ISI.

10 16. The method of claim 11, wherein the maximum impurity implantation concentration of the SOG layer additionally implanted with the impurity ions is adjusted to  $10^{19} - 10^{23} \text{ cm}^{-3}$ .

15 17. The method of claim 11, wherein the shallow junctions are formed by the solid phase diffusion method using one of rapid thermal annealing (RTA), spike annealing, and laser annealing.

20 18. The method of claim 17, wherein in the RTA, the semiconductor substrate on which the SOG layer having the increased concentration of impurities is formed is rapidly thermally annealed at a temperature of 950 – 1150 °C for 1 – 1000 seconds in an inert gas atmosphere.

25 19. The method of claim 17, wherein in the spike annealing, the semiconductor substrate on which the SOG layer having the increased concentration of impurities is formed is rapidly thermally annealed at a temperature of 950 – 1200 °C in an inert gas atmosphere.

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20. The method of claim 11, wherein the shallow junctions have a doping depth of 50nm or less on the semiconductor substrate and a doping concentration of  $10^{18} - 10^{22} \text{cm}^{-3}$ .